L Number	Hits	Search Text	DB	Time stamp
1	3031	(250/306,307,309,310).ccls.	USPAT; US-PGPUB	2004/08/16 10:51
2	2656	(324/751,765).ccls.	USPAT; US-PGPUB	2004/08/16 10:52
3	5573	((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)	USPAT; US-PGPUB	2004/08/16 10:53
4	42	(((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)) and (charged adj particle adj beam) and (inspect$ with circuit with pattern$2)	USPAT; US-PGPUB	2004/08/16 11:30
5	39	((((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)) and (charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 or foreign$7))	USPAT; US-PGPUB	2004/08/16 11:31
6	1	(((((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)) and (charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 or foreign$7))) and ((charging or (carbon$6 near3 deposit$3)) with mark$4)	USPAT; US-PGPUB	2004/08/16 11:10
7	1	(((((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)) and (charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 or foreign$7))) and ((charging or (carbon$6 near3 deposit$3)) with gas)	USPAT; US-PGPUB	2004/08/16 10:57
8	26	(((((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)) and (charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 or foreign$7))) and (charging or (carbon$6 near3 deposit$3))	USPAT; US-PGPUB	2004/08/16 11:11
9	25	((((((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)) and (charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 or foreign$7))) and (charging or (carbon$6 near3 deposit$3))) not ((((((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)) and (charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 or foreign$7))) and ((charging or (carbon$6 near3 deposit$3)) with gas))	USPAT; US-PGPUB	2004/08/16 10:58
10	13	(((((((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)) and (charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 or foreign$7))) and (charging or (carbon$6 near3 deposit$3))) not ((((((250/306,307,309,310).ccls.) or ((324/751,765).ccls.)) and (charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 or foreign$7))) and ((charging or (carbon$6 near3 deposit$3)) with gas))) and @pd<20021106	USPAT; US-PGPUB	2004/08/16 11:06
11	7	6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.	USPAT; US-PGPUB	2004/08/16 11:38
12	6	20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.	USPAT; US-PGPUB	2004/08/16 11:09

13	12	(6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)	USPAT; US-PGPUB	2004/08/16 11:09
14	0	((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and ((charging or (carbon$6 near3 deposit$3)) with mark$4)	USPAT; US-PGPUB	2004/08/16 11:10
15	12	((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))	USPAT; US-PGPUB	2004/08/16 11:10
16	12	(((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging or (carbon$6 near3 deposit$3))	USPAT; US-PGPUB	2004/08/16 11:13
17	0	(((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging with (carbon$6 near3 deposit$3))	USPAT; US-PGPUB	2004/08/16 11:13
18	0	(((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (carbon$6 near3 deposit$3)	USPAT; US-PGPUB	2004/08/16 11:32
19	12	(((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging)	USPAT; US-PGPUB	2004/08/16 11:27
20	0	(((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging with carbon$6)	USPAT; US-PGPUB	2004/08/16 11:14

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21	5	(((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging with deposit$6)	USPAT; US-PGPUB	2004/08/16 11:32
22	5	((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (charging with deposit$6))	USPAT; US-PGPUB	2004/08/16 11:27
23	7	((((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging)) not ((((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging with deposit$6))	USPAT; US-PGPUB	2004/08/16 11:27
24	8	(((((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging)) not ((((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging with deposit$6))) or 20010019411.pn.	USPAT; US-PGPUB	2004/08/16 11:28
25	1	((((((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging)) not ((((6172363.pn. or 6329826.pn. or 6335532.pn. or 6465781.pn. or 20010019411.pn. or 20010021020.pn. or 20020028399.pn.) or (20020134936.pn. or 20020117619.pn. or 20020109088.pn. or 20020084411.pn. or 20020033449.pn. or 20020028399.pn.)) and (imag$4 with (defect$4 or foreign$7))) and (charging with deposit$6))) or 20010019411.pn.) and ((second or two or another) near3 (inspection near2 apparatus))	USPAT; US-PGPUB	2004/08/16 11:32

26	114	(charged adj particle adj beam) and (inspect$ with circuit with pattern$2)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/16 11:30
27	24	((charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 with foreign$7))	USPAT; US-PGPUB	2004/08/16 11:43
28	18	(((charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 with foreign$7))) and (charging with deposit$6)	USPAT; US-PGPUB	2004/08/16 11:43
29	18	((((charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 with foreign$7))) and (charging with deposit$6)) and ((second or two or another) near3 (inspection near2 apparatus))	USPAT; US-PGPUB	2004/08/16 11:44
30	1	(((((charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 with foreign$7))) and (charging with deposit$6)) and ((second or two or another) near3 (inspection near2 apparatus))) and (carbon$6 near3 deposit$3)	USPAT; US-PGPUB	2004/08/16 11:44
31	17	(((((charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 with foreign$7))) and (charging with deposit$6)) and ((second or two or another) near3 (inspection near2 apparatus))) not ((((((charged adj particle adj beam) and (inspect$ with circuit with pattern$2)) and (imag$4 with (defect$4 with foreign$7))) and (charging with deposit$6)) and ((second or two or another) near3 (inspection near2 apparatus))) and (carbon$6 near3 deposit$3))	USPAT; US-PGPUB	2004/08/16 11:33
32	11	6388747.pn. or 6421122.pn. or 6476913.pn. or 6480279.pn. or 6493082.pn. or 6504609.pn. or 6567168.pn. or 6759655.pn. or 20010011706.pn. or 20010015805.pn. or 20010019411.pn.	USPAT; US-PGPUB	2004/08/16 11:41
33	6	20010021019.pn. or 20010021020.pn. or 20020105648.pn. or 20020109088.pn. or 20020113967.pn. or 20030058444.pn.	USPAT; US-PGPUB	2004/08/16 11:42
34	17	(20010021019.pn. or 20010021020.pn. or 20020105648.pn. or 20020109088.pn. or 20020113967.pn. or 20030058444.pn.) or (6388747.pn. or 6421122.pn. or 6476913.pn. or 6480279.pn. or 6493082.pn. or 6504609.pn. or 6567168.pn. or 6759655.pn. or 20010011706.pn. or 20010015805.pn. or 20010019411.pn.)	USPAT; US-PGPUB	2004/08/16 11:42
35	17	((20010021019.pn. or 20010021020.pn. or 20020105648.pn. or 20020109088.pn. or 20020113967.pn. or 20030058444.pn.) or (6388747.pn. or 6421122.pn. or 6476913.pn. or 6480279.pn. or 6493082.pn. or 6504609.pn. or 6567168.pn. or 6759655.pn. or 20010011706.pn. or 20010015805.pn. or 20010019411.pn.)) and (imag$4 with (defect$4 with foreign$7))	USPAT; US-PGPUB	2004/08/16 11:43

36	17	(((20010021019.pn. or 20010021020.pn. or 20020105648.pn. or 20020109088.pn. or 20020113967.pn. or 20030058444.pn.) or (6388747.pn. or 6421122.pn. or 6476913.pn. or 6480279.pn. or 6493082.pn. or 6504609.pn. or 6567168.pn. or 6759655.pn. or 20010011706.pn. or 20010015805.pn. or 20010019411.pn.)) and (imag$4 with (defect$4 with foreign$7))) and (charging with deposit$6)	USPAT; US-PGPUB	2004/08/16 11:43
37	0	((((20010021019.pn. or 20010021020.pn. or 20020105648.pn. or 20020109088.pn. or 20020113967.pn. or 20030058444.pn.) or (6388747.pn. or 6421122.pn. or 6476913.pn. or 6480279.pn. or 6493082.pn. or 6504609.pn. or 6567168.pn. or 6759655.pn. or 20010011706.pn. or 20010015805.pn. or 20010019411.pn.)) and (imag$4 with (defect$4 with foreign$7))) and (charging with deposit$6)) and (carbon$6 near3 deposit$3)	USPAT; US-PGPUB	2004/08/16 11:44
38	17	((((20010021019.pn. or 20010021020.pn. or 20020105648.pn. or 20020109088.pn. or 20020113967.pn. or 20030058444.pn.) or (6388747.pn. or 6421122.pn. or 6476913.pn. or 6480279.pn. or 6493082.pn. or 6504609.pn. or 6567168.pn. or 6759655.pn. or 20010011706.pn. or 20010015805.pn. or 20010019411.pn.)) and (imag$4 with (defect$4 with foreign$7))) and (charging with deposit$6)) and ((second or two or another) near3 (inspection near2 apparatus))	USPAT; US-PGPUB	2004/08/16 11:44

	U	1	Document ID	Issue Date	Pages	Title	Current OR
1	☐	☐	US 20030058444 A1	20030327	61	Inspection method, apparatus and system for circuit pattern	356/394
2	☒	☐	US 20020113967 A1	20020822	61	Inspection method, apparatus and system for circuit pattern	356/394
3	☒	☐	US 20020109088 A1	20020815	60	Inspection method, apparatus and system for circuit pattern	250/306
4	☒	☐	US 20020105648 A1	20020808	60	Inspection method, apparatus and system for circuit pattern	356/394
5	☐	☐	US 20010021020 A1	20010913	60	Inspection method, apparatus and system for circuit pattern	356/394
6	☒	☐	US 20010021019 A1	20010913	60	Inspection method, apparatus and system for circuit pattern	356/394
7	☒	☒	US 20010019411 A1	20010906	61	Inspection method, apparatus and system for circuit pattern	356/394
8	☒	☐	US 20010015805 A1	20010823	61	Inspection method, apparatus and system for circuit pattern	356/394
9	☒	☐	US 20010011706 A1	20010809	62	Inspection method, apparatus and system for circuit pattern	250/397
10	☒	☐	US 6759655 B2	20040706	59	Inspection method, apparatus and system for circuit pattern	250/310
11	☒	☐	US 6567168 B2	20030520	62	Inspection method, apparatus and system for circuit pattern	356/394
12	☒	☐	US 6504609 B2	20030107	59	Inspection method, apparatus and system for circuit pattern	356/394
13	☒	☐	US 6493082 B2	20021210	59	Inspection method, apparatus and system for circuit pattern	356/394
14	☒	☐	US 6480279 B2	20021112	59	Inspection method, apparatus and system for circuit pattern	356/394
15	☐	☐	US 6476913 B1	20021105	62	Inspection method, apparatus and system for circuit pattern	356/394
16	☐	☐	US 6421122 B2	20020716	63	Inspection method, apparatus and system for circuit pattern	356/394
17	☐	☒	US 6388747 B2	20020514	59	Inspection method, apparatus and system for circuit pattern	356/394

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5
1			Nara, Yasuhiko et al.	☒	☐	☐	☐	☐	☐	☐
2			Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
3	250/309; 250/310; 250/311		Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
4			Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
5	250/310; 250/559.34		Nara, Yasuhiko et al.	☒	☐	☐	☐	☐	☐	☐
6			Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
7	250/307; 250/310; 356/237.2		Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
8			Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
9			Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
10	250/307		Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
11	250/310	.	Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
12			Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
13	382/145		Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
14	382/145		Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
15			Machida, Kazuhisa et al.	☒	☐	☐	☐	☐	☐	☐
16	382/145		Nara, Yasuhiko et al.	☒	☐	☐	☐	☐	☐	☐
17			Nara, Yasuhiko et al.	☒	☐	☐	☐	☐	☐	☐

	Image Doc. Displayed	PT
1	US 20030058444	☐
2	US 20020113967	☐
3	US 20020109088	☐
4	US 20020105648	☐
5	US 20010021020	☐
6	US 20010021019	☐
7	US 20010019411	☐
8	US 20010015805	☐
9	US 20010011706	☐
10	US 6759655	☐
11	US 6567168	☐
12	US 6504609	☐
13	US 6493082	☐
14	US 6480279	☐
15	US 6476913	☐
16	US 6421122	☐
17	US 6388747	☐

	U	1	Document ID	Issue Date	Pages	Title	Current OR
1	☐	☐	US 20020134936 A1	20020926	24	Wafer inspection system and wafer inspection process using charged particle beam	250/310
2	☒	☐	US 20020117619 A1	20020829	13	INSPECTING SYSTEM USING ELECTRON BEAM AND INSPECTING METHOD USING SAME	250/310
3	☒	☐	US 20020109088 A1	20020815	60	Inspection method, apparatus and system for circuit pattern	250/306
4	☒	☐	US 20020084411 A1	20020704	12	Substrate inspection system and method for controlling same	250/306
5	☒	☒	US 20020033449 A1	20020321	128	Inspection system by charged particle beam and method of manufacturing devices using the system	250/306
6	☒	☐	US 20020028399 A1	20020307	102	Inspection system by charged particle beam and method of manufacturing devices using the system	430/30
7	☒	☐	US 20020027440 A1	20020307	41	Method and apparatus for inspecting integrated circuit pattern	324/751
8	☒	☐	US 20010021020 A1	20010913	60	Inspection method, apparatus and system for circuit pattern	356/394
9	☒	☐	US 20010019411 A1	20010906	61	Inspection method, apparatus and system for circuit pattern	356/394
10	☒	☐	US 6465781 B1	20021015	32	Method and apparatus for inspecting or measuring a sample based on charged-particle beam imaging, and a charged-particle beam apparatus	250/306
11	☒	☐	US 6335532 B1	20020101	37	Convergent charged particle beam apparatus and inspection method using same	250/491.1
12	☒	☐	US 6329826 B1	20011211	37	Method and apparatus for inspecting integrated circuit pattern	324/751

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5
1			Matsui, Miyako et al.	☒	☐	☐	☐	☐	☐	☐
2	250/307		Gunji, Yasuhiro et al.	☐	☐	☐	☐	☐	☐	☐
3	250/309; 250/310; 250/311		Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
4			Yamazaki, Yuichiro et al.	☐	☐	☐	☐	☐	☐	☐
5			Nakasuji, Mamoru et al.	☐	☐	☐	☐	☐	☐	☐
6	250/306; 356/237.5; 430/296		Nakasuji, Mamoru et al.	☐	☐	☐	☐	☐	☐	☐
7			Shinada, Hiroyuki et al.	☐	☐	☐	☐	☐	☐	☐
8	250/310; 250/559.34		Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
9	250/307; 250/310; 356/237.2		Nara, Yasuhiko et al.	☐	☐	☐	☐	☐	☐	☐
10	250/305; 250/307; 250/308; 250/311		Nishimura, Norimasa et al.	☐	☐	☐	☐	☐	☐	☐
11	250/310; 250/397; 250/398; 250/492.2		Tanaka, Maki et al.	☐	☐	☐	☐	☐	☐	☐
12	324/765		Shinada, Hiroyuki et al.	☐	☐	☐	☐	☐	☐	☐

	Image Doc. Displayed	PT
1	US 20020134936	☐
2	US 20020117619	☐
3	US 20020109088	☐
4	US 20020084411	☐
5	US 20020033449	☐
6	US 20020028399	☐
7	US 20020027440	☐
8	US 20010021020	☐
9	US 20010019411	☐
10	US 6465781	☐
11	US 6335532	☐
12	US 6329826	☐

	U	1	Document ID	Issue Date	Pages	Title	Current OR
13	☐	☐	US 6172363 B1	20010109	38	Method and apparatus for inspecting integrated circuit pattern	250/310

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5
13	250/307		Shinada, Hiroyuki et al.	☒	☐	☐	☐	☐	☐	☐

	Image Doc. Displayed	PT
13	US 6172363	☐